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For: METHOD AND SYSTEM OF CHARACTERIZING A DEVICE
UNDER TEST

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ABSTRACT OF DISCLOSURE

A system and method of characterizing a device under test wherein a signal is injected into the device under test, the response to the injected signal is measured to determine the impedance of the device under test in the frequency domain, the impedance is converted to the time domain, and the voltage noise of the device under test is calculated based on the impedance of the device under test in the time domain.

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